Power MOSFET 90 Amps, 24 Volts N-Channel D²PAK and TO-220

Designed for low voltage, high speed switching applications in power supplies, converters and power motor controls and bridge circuits.

Typical Applications

- Power Supplies
- Converters
- Power Motor Controls
- Bridge Circuits

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

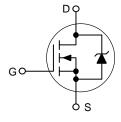
Rating	Symbol	Value	Unit			
Drain-to-Source Voltage	V _{DSS}	24	Vdc			
Gate-to-Source Voltage - Continuous	V _{GS}	±20	Vdc			
Drain Current – Continuous @ T _A = 25°C – Single Pulse (t _p = 10 μs)	I _D I _{DM}	90* 200	A A			
Total Power Dissipation @ T _A = 25°C Derate above 25°C	PD	85 0.66	W W/°C			
Operating and Storage Temperature	T _J , T _{stg}	-55 to +150	°C			
$ Single Pulse Drain-to-Source Avalanche \\ Energy - Starting T_J = 25^\circ C \\ (V_{DD} = 28 \ Vdc, \ V_{GS} = 10 \ Vdc, \ L = 5.0 \ mH, \\ I_{L(pk)} = 17 \ A, \ RG = 25 \ \Omega) $	E _{AS}	733	mJ			
Thermal Resistance Junction-to-Case Junction-to-Ambient (Note 1)	$R_{ extsf{ heta}JC} \\ R_{ hetaJA}$	1.55 70	°C/W			
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds	ΤL	260	°C			

1. When surface mounted to an FR4 board using 1" pad size, (Cu Area 1.127 in²).

 When surface mounted to an FR4 board using minimum recommended pad size, (Cu Area 0.412 in²).

*Chip current capability limited by package.



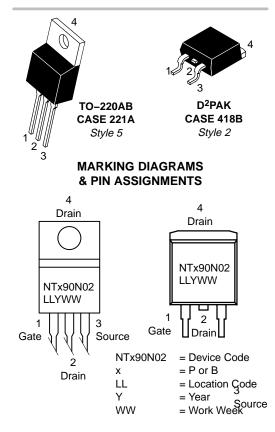




ON Semiconductor®

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V _{(BR)DSS}	R _{DS(on)} TYP	I _D MAX
24 V	5.0 m Ω @ 10 V	90 A
	7.5 mΩ @ 4.5 V	0077



ORDERING INFORMATION

Device	Package	Shipping [†]
NTP90N02	TO-220AB	50 Units/Rail
NTB90N02	D ² PAK	50 Units/Rail
NTB90N02T4	D ² PAK	800/Tape & Reel

⁺For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise noted)

C	Symbol	Min	Тур	Мах	Unit	
OFF CHARACTERISTICS						
$\begin{array}{l} \text{Drain-to-Source Breakdown} \\ (\text{V}_{\text{GS}} = 0 \ \text{Vdc}, \ \text{I}_{\text{D}} = 250 \ \mu\text{Adv} \\ Temperature Coefficient (Positi$	V _{(BR)DSS}	24 -	27 25		Vdc mV/°C	
Zero Gate Voltage Drain Current $(V_{DS} = 24 \text{ Vdc}, V_{GS} = 0 \text{ Vdc})$ $(V_{DS} = 24 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}, T_J = 150^{\circ}\text{C})$					1.0 10	μAdc
Gate-Body Leakage Current ($V_{GS} = \pm 20 \text{ Vdc}, V_{DS} = 0 \text{ Vdc})$	I _{GSS}	-	-	±100	nAdc
ON CHARACTERISTICS (Note	3)					•
Gate Threshold Voltage (Note $(V_{DS} = V_{GS}, I_D = 250 \ \mu Adc)$ Threshold Temperature Coeffic	V _{GS(th)}	1.0 -	1.9 -3.8	3.0 -	Vdc mV/°C	
$\begin{array}{l} \text{Static Drain-to-Source On-Re} \\ (\text{V}_{\text{GS}} = 10 \ \text{Vdc}, \ \text{I}_{\text{D}} = 90 \ \text{Adc}) \\ (\text{V}_{\text{GS}} = 4.5 \ \text{Vdc}, \ \text{I}_{\text{D}} = 40 \ \text{Adc}) \\ (\text{V}_{\text{GS}} = 10 \ \text{Vdc}, \ \text{I}_{\text{D}} = 20 \ \text{Adc}) \\ (\text{V}_{\text{GS}} = 4.5 \ \text{Vdc}, \ \text{I}_{\text{D}} = 20 \ \text{Adc}) \end{array}$	R _{DS(on)}	- - - -	5.0 7.5 5.0 7.5	5.8 9.0 5.8 9.0	mΩ	
Forward Transconductance (N	9 FS	-	25	-	mhos	
DYNAMIC CHARACTERISTIC	S		1		•	•
Input Capacitance	$(V_{DS} = 20 \text{ Vdc}, V_{GS} = 0 \text{ Vdc},$	C _{iss}	-	2120	_	pF
Output Capacitance	f = 1.0 MHz)	C _{oss}	-	900	-	1
Transfer Capacitance		C _{rss}	-	360	-	
SWITCHING CHARACTERIST	ICS (Note 4)					
Turn-On Delay Time	$(V_{DD} = 20 \text{ Vdc}, I_D = 20 \text{ Adc},$	t _{d(on)}	-	16	-	ns
Rise Time	- V _{GS} = 4.5 Vdc, R _G = 2.5 Ω)	t _r	-	90	-	
Turn–Off Delay Time		t _{d(off)}	-	28	-	
Fall Time		t _f	-	60	-	
Gate Charge	$(V_{DS} = 20 \text{ Vdc}, I_D = 20 \text{ Adc},$	Q _T	-	29	-	nC
	V _{GS} = 4.5 Vdc) (Note 3)	Q ₁	-	8.0	-	7
		Q ₂	-	20	_	
SOURCE-DRAIN DIODE CHA	RACTERISTICS					
Forward On–Voltage		V _{SD}		0.75 1.2 0.65	1.0 _ _	Vdc
Reverse Recovery Time	$(I_{S} = 2.3 \text{ Adc}, V_{GS} = 0 \text{ Vdc},$	t _{rr}	-	40	-	ns
	dI _S /dt = 100 A/µs) (Note 3)	ta	-	21	-	1
				+	L	-

Reverse Recovery Stored Charge

tb

 $\mathsf{Q}_{\mathsf{R}\mathsf{R}}$

18

0.036

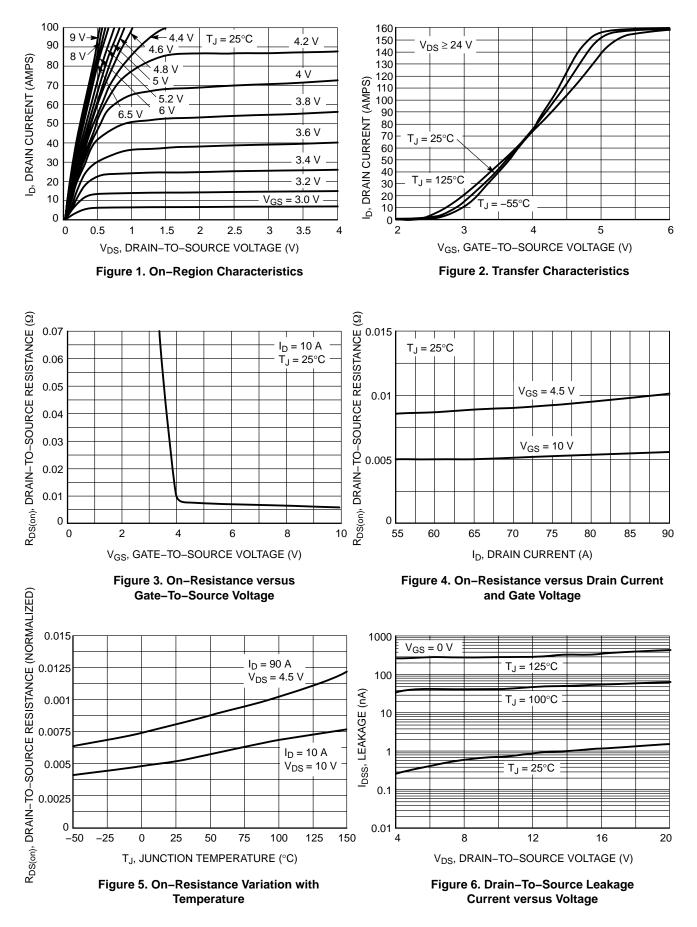
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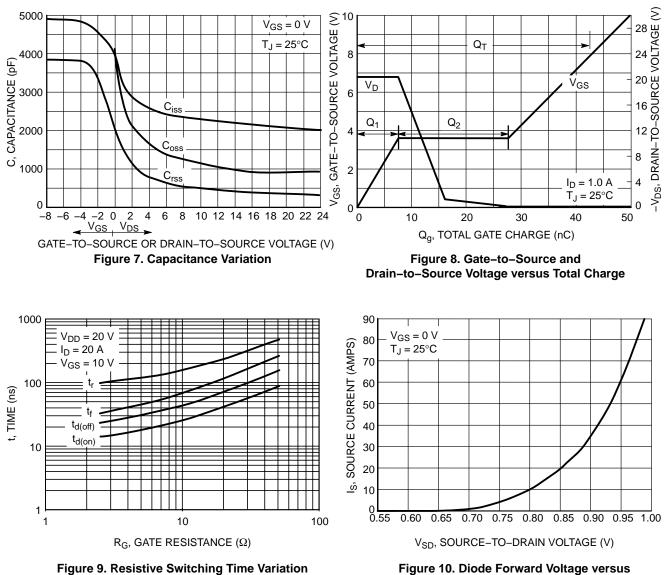
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μC





Current

versus Gate Resistance

http://onsemi.com 4

POWER MOSFET SWITCHING

Switching behavior is most easily modeled and predicted by recognizing that the power MOSFET is charge controlled. The lengths of various switching intervals (Δt) are determined by how fast the FET input capacitance can be charged by current from the generator.

The published capacitance data is difficult to use for calculating rise and fall because drain–gate capacitance varies greatly with applied voltage. Accordingly, gate charge data is used. In most cases, a satisfactory estimate of average input current ($I_{G(AV)}$) can be made from a rudimentary analysis of the drive circuit so that

$$t = Q/IG(AV)$$

During the rise and fall time interval when switching a resistive load, V_{GS} remains virtually constant at a level known as the plateau voltage, V_{SGP} . Therefore, rise and fall times may be approximated by the following:

$$t_r = Q_2 \times R_2 / 10(V_{GG} - V_{GSP})$$

$$t_f = Q_2 \times R_2 / V_{GSP}$$

where:

 V_{GG} = the gate drive voltage, which varies from zero to V_{GG}

 R_G = the gate drive resistance and Q_2 and V_{GSP} are read from the gate charge curve.

During the turn–on and turn–off delay times, gate current is not constant. The simplest calculation uses appropriate values from the capacitance curves in a standard equation for voltage change in an RC network.

The equations are:

 $t_{d(on)} = R_G C_{iss} ln [V_{GG}/(V_{GG} - V_{GSP})]$

 $t_{d(off)} = R_G C_{iss} ln (V_{GG}/V_{GSP})$

The capacitance (C_{iss}) is read from the capacitance curve at a voltage corresponding to the off–state condition when calculating $t_{d(on)}$ and is read at a voltage corresponding to the on–state when calculating $t_{d(off)}$.

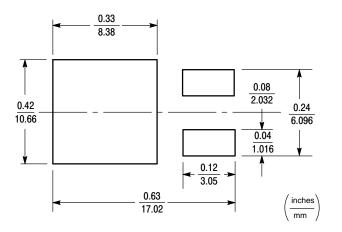
At high switching speeds, parasitic circuit elements complicate the analysis. The inductance of the MOSFET source lead, inside the package and in the circuit wiring which is common to both the drain and gate current paths, produces a voltage at the source which reduces the gate drive current. The voltage is determined by Ldi/dt, but since di/dt is a function of drain current, the mathematical solution is complex. The MOSFET output capacitance also complicates the mathematics. And finally, MOSFETs have finite internal gate resistance which effectively adds to the resistance of the driving source, but the internal resistance is difficult to measure and, consequently, is not specified.

The resistive switching time variation versus gate resistance (Figure 9) shows how typical switching performance is affected by the parasitic circuit elements. If the parasitics were not present, the slope of the curves would maintain a value of unity regardless of the switching speed. The circuit used to obtain the data is constructed to minimize common inductance in the drain and gate circuit loops and is believed readily achievable with board mounted components. Most power electronic loads are inductive; the data in the figure is taken with a resistive load, which approximates an optimally snubbed inductive load. Power MOSFETs may be safely operated into an inductive load; however, snubbing reduces switching losses.

INFORMATION FOR USING THE D²PAK SURFACE MOUNT PACKAGE RECOMMENDED FOOTPRINT FOR SURFACE MOUNTED APPLICATIONS

Surface mount board layout is a critical portion of the total design. The footprint for the semiconductor packages must be the correct size to ensure proper solder connection

interface between the board and the package. With the correct pad geometry, the packages will self align when subjected to a solder reflow process.



SOLDER STENCIL GUIDELINES

Prior to placing surface mount components onto a printed circuit board, solder paste must be applied to the pads. Solder stencils are used to screen the optimum amount. These stencils are typically 0.008 inches thick and may be made of brass or stainless steel. For packages such as the SC-59, SC-70/SOT-323, SOD-123, SOT-23, SOT-143, SOT-223, SO-8, SO-14, SO-16, and SMB/SMC diode packages, the stencil opening should be the same as the pad size or a 1:1 registration. This is not the case with the DPAK and D²PAK packages. If one uses a 1:1 opening to screen solder onto the drain pad, misalignment and/or "tombstoning" may occur due to an excess of solder. For these two packages, the opening in the stencil for the paste should be approximately 50% of the tab area. The opening for the leads is still a 1:1 registration. Figure 11 shows a typical stencil for the DPAK and D²PAK packages. The

pattern of the opening in the stencil for the drain pad is not critical as long as it allows approximately 50% of the pad to be covered with paste.

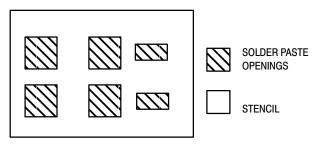


Figure 11. Typical Stencil for DPAK and D²PAK Packages

SOLDERING PRECAUTIONS

The melting temperature of solder is higher than the rated temperature of the device. When the entire device is heated to a high temperature, failure to complete soldering within a short time could result in device failure. Therefore, the following items should always be observed in order to minimize the thermal stress to which the devices are subjected.

- Always preheat the device.
- The delta temperature between the preheat and soldering should be 100°C or less.*
- When preheating and soldering, the temperature of the leads and the case must not exceed the maximum temperature ratings as shown on the data sheet. When using infrared heating with the reflow soldering method, the difference shall be a maximum of 10°C.
- The soldering temperature and time shall not exceed 260°C for more than 10 seconds.

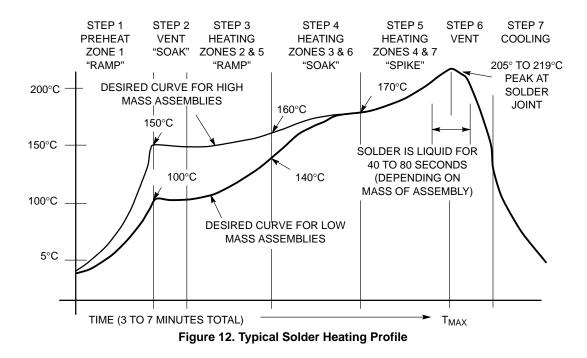
- When shifting from preheating to soldering, the maximum temperature gradient shall be 5°C or less.
- After soldering has been completed, the device should be allowed to cool naturally for at least three minutes. Gradual cooling should be used as the use of forced cooling will increase the temperature gradient and result in latent failure due to mechanical stress.
- Mechanical stress or shock should not be applied during cooling.

* * Soldering a device without preheating can cause excessive thermal shock and stress which can result in damage to the device.

* * Due to shadowing and the inability to set the wave height to incorporate other surface mount components, the D^2PAK is not recommended for wave soldering.

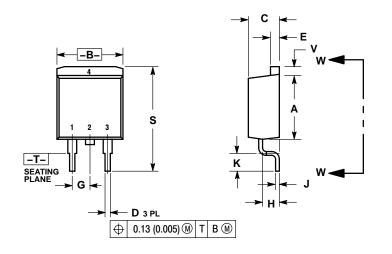
TYPICAL SOLDER HEATING PROFILE

For any given circuit board, there will be a group of control settings that will give the desired heat pattern. The operator must set temperatures for several heating zones, and a figure for belt speed. Taken together, these control settings make up a heating "profile" for that particular circuit board. On machines controlled by a computer, the computer remembers these profiles from one operating session to the next. Figure 12 shows a typical heating profile for use when soldering a surface mount device to a printed circuit board. This profile will vary among soldering systems but it is a good starting point. Factors that can affect the profile include the type of soldering system in use, density and types of components on the board, type of solder used, and the type of board or substrate material being used. This profile shows temperature versus time. The line on the graph shows the actual temperature that might be experienced on the surface of a test board at or near a central solder joint. The two profiles are based on a high density and a low density board. The Vitronics SMD310 convection/infrared reflow soldering system was used to generate this profile. The type of solder used was 62/36/2 Tin Lead Silver with a melting point between 177–189°C. When this type of furnace is used for solder reflow work, the circuit boards and solder joints tend to heat first. The components on the board are then heated by conduction. The circuit board, because it has a large surface area, absorbs the thermal energy more efficiently, then distributes this energy to the component may be up to 30 degrees cooler than the adjacent solder joint.



PACKAGE DIMENSIONS

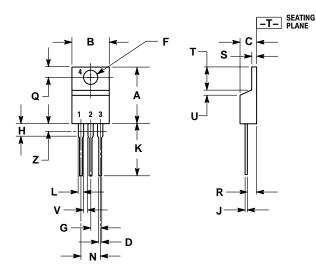
D²PAK CASE 418B-04 **ISSUE H**



1. 2.	NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH. 3. 418B–01 THRU 418B–03 OBSOLETE, NEW STANDARD 418B–04.					
		INCHES		MILLIN	IETERS	
	DIM	MIN	MAX	MIN	MAX	
	Α	0.340	0.380	8.64	9.65	
	в	0.380	0.405	9.65	10.29	
	c	0.160	0.190	4.06	4.83	
	D	0.020	0.035	0.51	0.89	
	Е	0.045	0.055	1.14	1.40	
	F	0.310	0.350	7.87	8.89	
	G	0.100	BSC	2.54	BSC	
	Н	0.080	0.110	2.03	2.79	
	J	0.018	0.025	0.46	0.64	
	κ	0.090	0.110	2.29	2.79	
	L	0.052	0.072	1.32	1.83	
	M	0.280	0.320	7.11	8.13	
	Ν	0.197	REF	5.00	REF	
	Р	0.079	REF	2.00	REF	
	R	0.039	REF	0.99	REF	
	S	0.575	0.625	14.60	15.88	
	V	0.045	0.055	1.14	1.40	

STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE 4. DRAIN

TO-220 CASE 221A-09 **ISSUE AA**



NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH. 3. DIMENSION Z DEFINES A ZONE WHERE ALL BODY AND LEAD IRREGULARITIES ARE ALLOWED.

	INCHES		MILLIMETERS	
DIM	MIN	MAX	MIN	MAX
Α	0.570	0.620	14.48	15.75
В	0.380	0.405	9.66	10.28
С	0.160	0.190	4.07	4.82
D	0.025	0.035	0.64	0.88
F	0.142	0.147	3.61	3.73
G	0.095	0.105	2.42	2.66
Н	0.110	0.155	2.80	3.93
J	0.018	0.025	0.46	0.64
Κ	0.500	0.562	12.70	14.27
L	0.045	0.060	1.15	1.52
Ν	0.190	0.210	4.83	5.33
Q	0.100	0.120	2.54	3.04
R	0.080	0.110	2.04	2.79
S	0.045	0.055	1.15	1.39
Т	0.235	0.255	5.97	6.47
U	0.000	0.050	0.00	1.27
۷	0.045		1.15	
Ζ		0.080		2.04

STYLE 5: PIN 1. GATE 2. DRAIN 3. SOURCE 4. DRAIN

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